

## N-Channel Power MOSFET (7A, 600Volts)

### DESCRIPTION

The Nell 7N60 is a three-terminal silicon device with current conduction capability of 7A, fast switching speed, low on-state resistance, breakdown voltage rating of 600V, and max. threshold voltage of 4 volts.

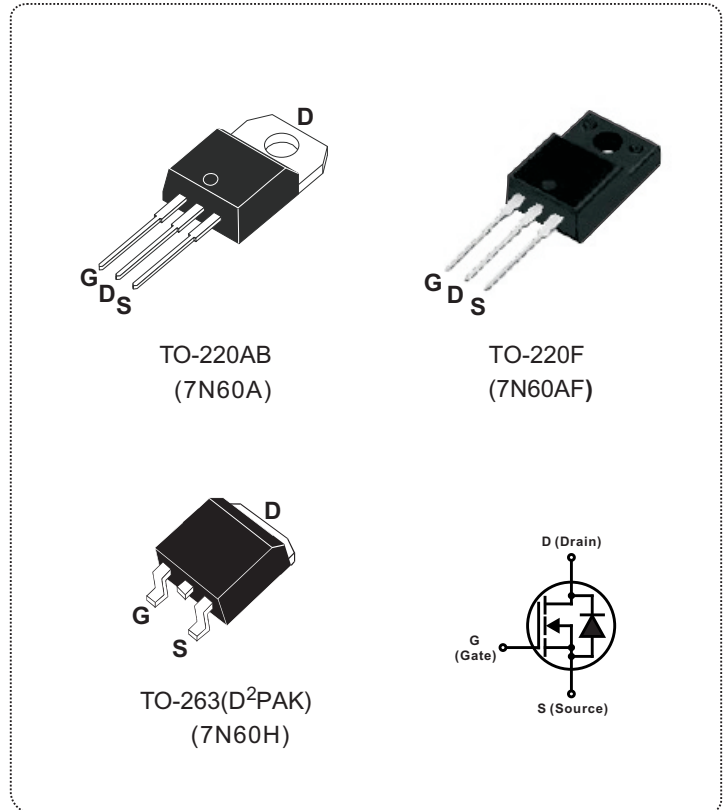
They are designed for use in applications, such as switched mode power supplies, DC to DC converters, **PWM** motor controls, bridge circuits, and general purpose switching applications.

### FEATURES

- $R_{DS(ON)} = 1.2\Omega @ V_{GS} = 10V$
- Ultra low gate charge(38nC max.)
- Low reverse transfer capacitance ( $C_{RSS} = 16pF$  typical)
- Fast switching capability
- 100% avalanche energy specified
- Improved dv/dt capability
- 150°C operation temperature

### PRODUCT SUMMARY

$I_D$ (A)	7
$V_{DSS}$ (V)	600
$R_{DS(ON)}$ ( $\Omega$ )	1.2 @ $V_{GS} = 10V$
$Q_G$ (nC) max.	38



### ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ C$ unless otherwise specified)

SYMBOL	PARAMETER	TEST CONDITIONS	VALUE	UNIT
$V_{DSS}$	Drain to Source voltage	$T_J = 25^\circ C$ to $150^\circ C$	600	V
$V_{DGR}$	Drain to Gate voltage	$R_{GS} = 20K\Omega$	600	
$V_{GS}$	Gate to Source voltage		$\pm 30$	
$I_D$	Continuous Drain Current	$T_C = 25^\circ C$	7	A
		$T_C = 100^\circ C$	4.3	
$I_{DM}$	Pulsed Drain current(Note 1)		28	
$I_{AR}$	Avalanche current(Note 1)		7	
$E_{AR}$	Repetitive avalanche energy(Note 1)	$I_{AR} = 7A, R_{GS} = 50\Omega, V_{GS} = 10V$	14	mJ
$E_{AS}$	Single pulse avalanche energy(Note 2)	$I_{AS} = 7A, L = 19.5mH$	500	
dv/dt	Peak diode recovery dv/dt(Note 3)		4.5	V/ns
$P_D$	Total power dissipation	$T_C = 25^\circ C$ TO-220AB/TO-263	140	W
		TO-220F	48	
$T_J$	Operation junction temperature		-55 to 150	$^\circ C$
$T_{STG}$	Storage temperature		-55 to 150	
$T_L$	Maximum soldering temperature, for 10 seconds	1.6mm from case	300	
	Mounting torque, #6-32 or M3 screw		10 (1.1)	lbf-in (N·m)

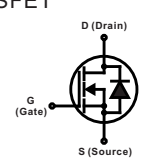
Note: 1. Repetitive rating: pulse width limited by junction temperature..

2.  $I_{AS} = 7A, V_{DD} = 50V, L = 19.5mH, R_{GS} = 25\Omega$ , starting  $T_J = 25^\circ C$ .

3.  $I_{SD} \leq 7A, di/dt \leq 200A/\mu s, V_{DD} \leq V_{(BR)DSS}$ , starting  $T_J = 25^\circ C$ .

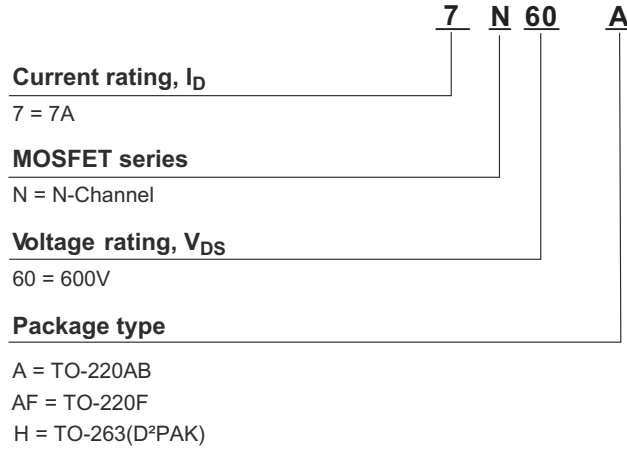
THERMAL RESISTANCE						
SYMBOL	PARAMETER		Min.	Typ.	Max.	UNIT
$R_{th(j-c)}$	Thermal resistance, junction to case	TO-220AB/TO-263			0.85	°C/W
		TO-220F			2.5	
$R_{th(j-a)}$	Thermal resistance, junction to ambient	TO-220AB/TO-263			62.5	
		TO-220F			62.5	

ELECTRICAL CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ unless otherwise specified)						
SYMBOL	PARAMETER	TEST CONDITIONS	Min.	Typ.	Max.	UNIT
$V_{(BR)DSS}$	Drain to source breakdown voltage	$I_D = 250\mu\text{A}, V_{GS} = 0\text{V}$	600			V
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown voltage temperature coefficient	$I_D = 250\mu\text{A}, V_{DS} = V_{GS}$		0.53		V/°C
$I_{DSS}$	Drain to source leakage current	$V_{DS} = 600\text{V}, V_{GS} = 0\text{V}$ $T_C = 25^\circ\text{C}$			10	$\mu\text{A}$
		$V_{DS} = 480\text{V}, V_{GS} = 0\text{V}$ $T_C = 125^\circ\text{C}$			100	
$I_{GSS}$	Gate to source forward leakage current	$V_{GS} = 30\text{V}, V_{DS} = 0\text{V}$			100	nA
	Gate to source reverse leakage current	$V_{GS} = -30\text{V}, V_{DS} = 0\text{V}$			-100	
$R_{DS(ON)}$	Static drain to source on-state resistance	$I_D = 3.5\text{A}, V_{GS} = 10\text{V}$		0.95	1.2	$\Omega$
$V_{GS(TH)}$	Gate threshold voltage	$V_{GS} = V_{DS}, I_D = 250\mu\text{A}$	2		4	V
$C_{ISS}$	Input capacitance	$V_{DS} = 25\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$			1400	pF
$C_{OSS}$	Output capacitance				180	
$C_{RSS}$	Reverse transfer capacitance			16	21	
$t_{d(ON)}$	Turn-on delay time	$V_{DD} = 300\text{V}, V_{GS} = 10\text{V}, I_D = 7\text{A}, R_{GS} = 25\Omega$ (Note 1, 2)			70	ns
$t_r$	Rise time				170	
$t_{d(OFF)}$	Turn-off delay time				140	
$t_f$	Fall time				130	
$Q_G$	Total gate charge	$V_{DD} = 480\text{V}, V_{GS} = 10\text{V}, I_D = 7\text{A}$ (Note 1, 2)		28	38	nC
$Q_{GS}$	Gate to source charge			7		
$Q_{GD}$	Gate to drain charge (Miller charge)			14		

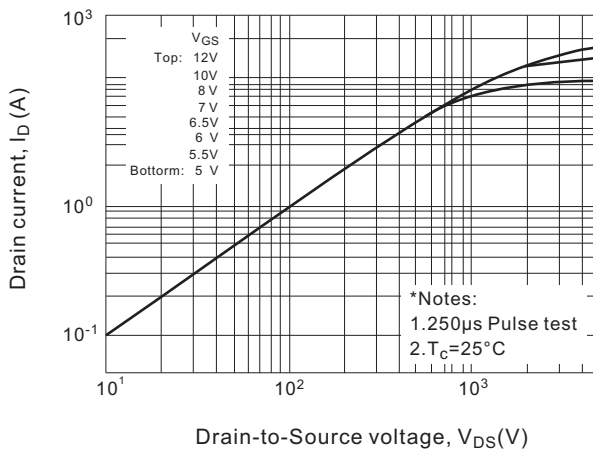
SOURCE TO DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ unless otherwise specified)						
SYMBOL	PARAMETER	TEST CONDITIONS	Min.	Typ.	Max.	UNIT
$V_{SD}$	Diode forward voltage	$I_{SD} = 7\text{A}, V_{GS} = 0\text{V}$			1.4	V
$I_S (I_{SD})$	Continuous source to drain current	Integral reverse P-N junction diode in the MOSFET 			7	A
$I_{SM}$	Pulsed source current				28	
$t_{rr}$	Reverse recovery time	$I_{SD} = 7\text{A}, V_{GS} = 0\text{V}, dI_F/dt = 100\text{A}/\mu\text{s}$		320		ns
$Q_{rr}$	Reverse recovery charge			2.4		$\mu\text{C}$

Note: 1. Pulse test: Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .  
 2. Essentially independent of operating temperature.

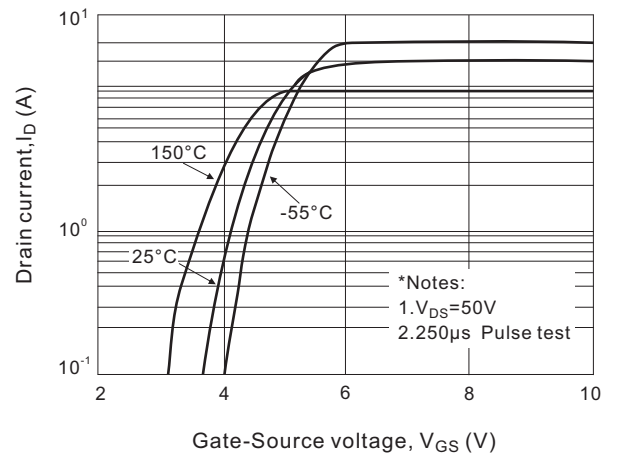
### ORDERING INFORMATION SCHEME



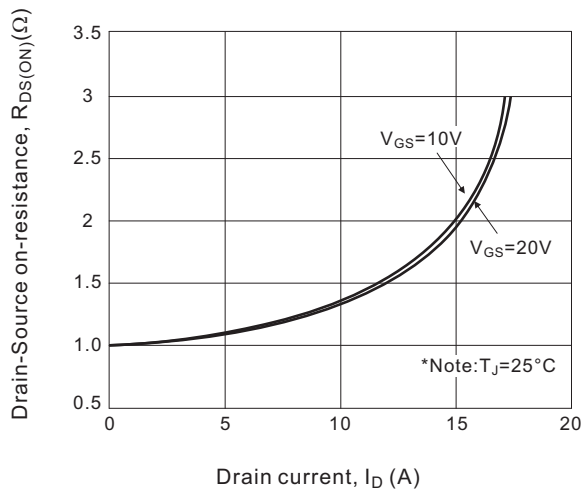
**Fig.1 On-State characteristics**



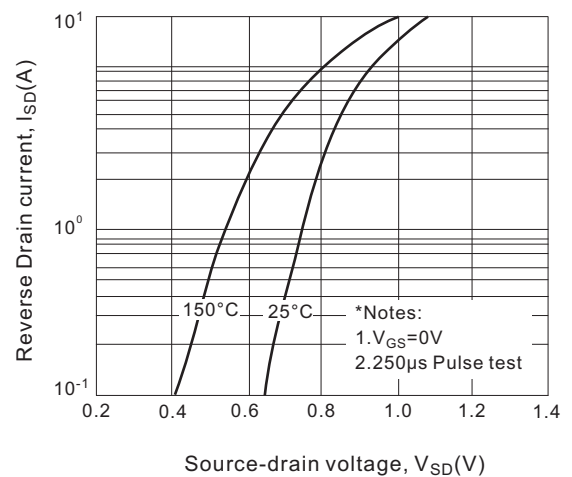
**Fig.2 Transfer characteristics**



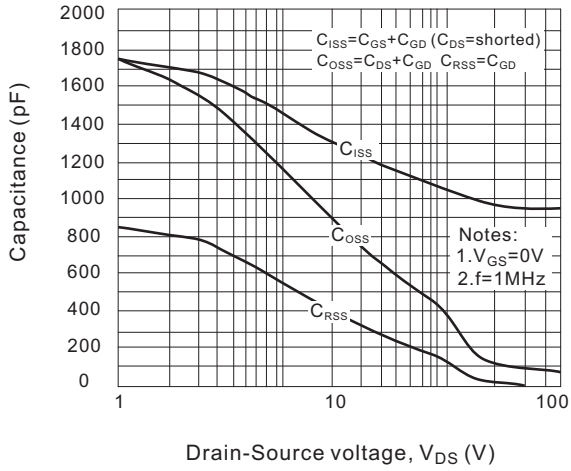
**Fig.3 On-resistance variation vs. drain current and gate voltage**



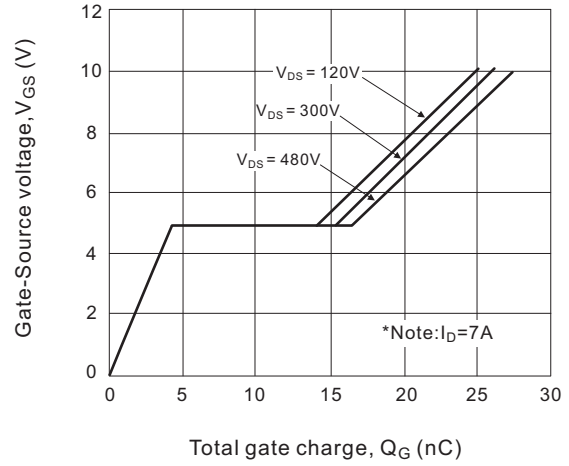
**Fig.4 Body diode forward voltage variation with source current and temperature**



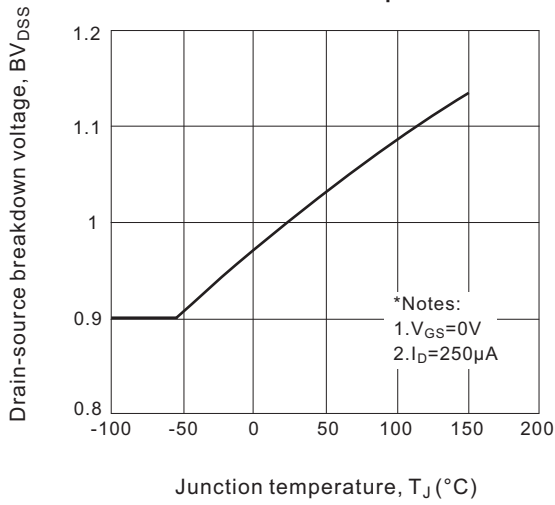
**Fig.5 Capacitance characteristics**



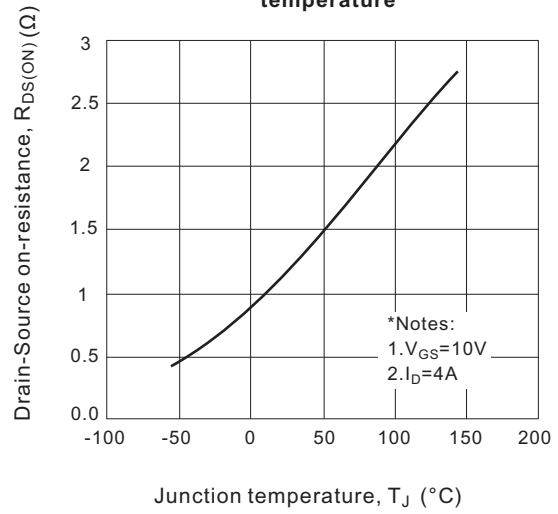
**Fig.6 Gate charge characteristics**



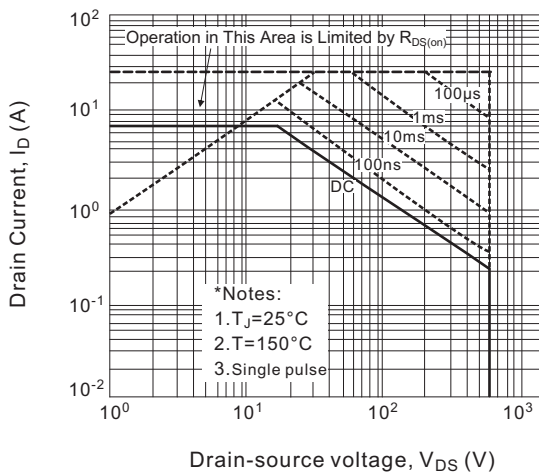
**Fig.7 Breakdown voltage variation vs. Junction temperature**



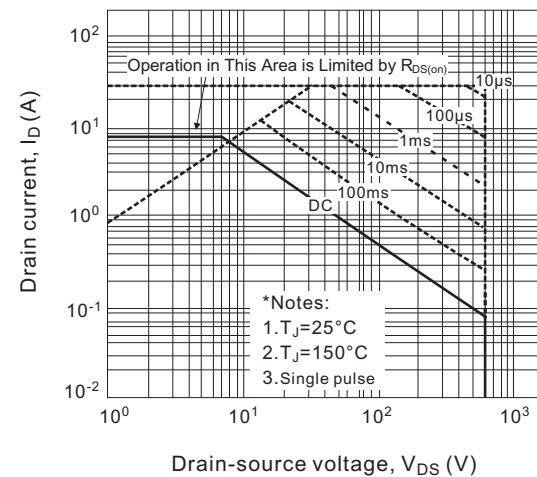
**Fig.8 On-resistance variation vs. Junction temperature**



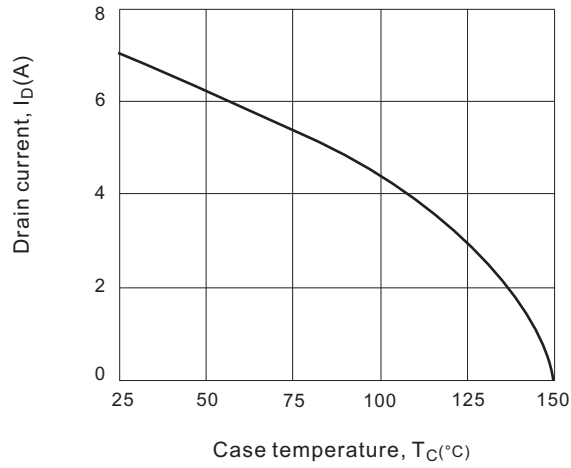
**Fig.9 Maximum safe operating area for TO-220**



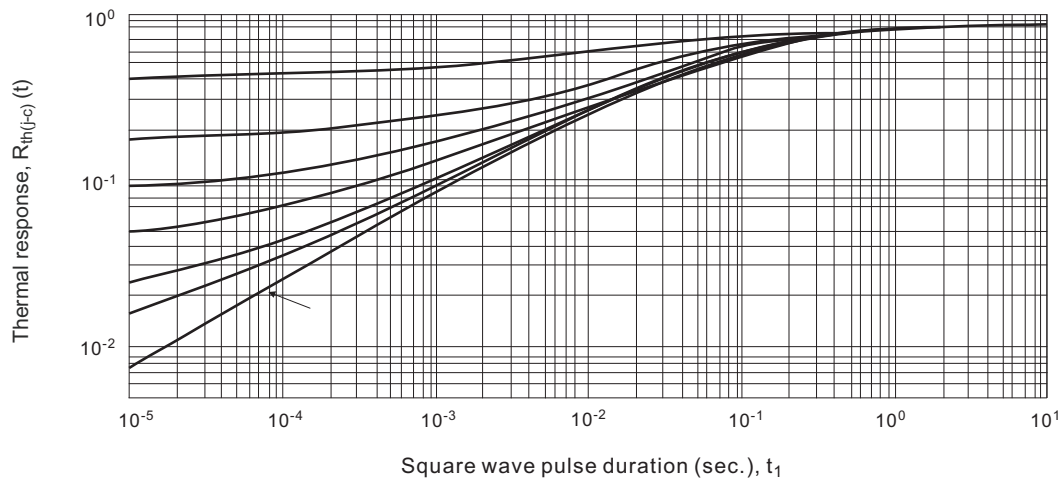
**Fig.10 Maximum safe operating area for TO-220F**



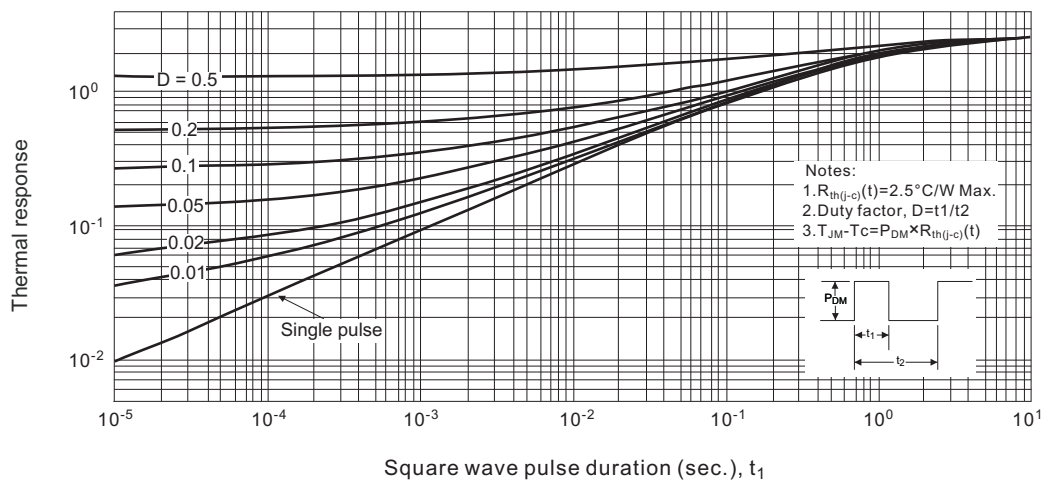
**Fig.11 Maximum drain current vs. case temperature**



**Fig.12 Transient thermal response curve (for 7N60A & 7N60H)**

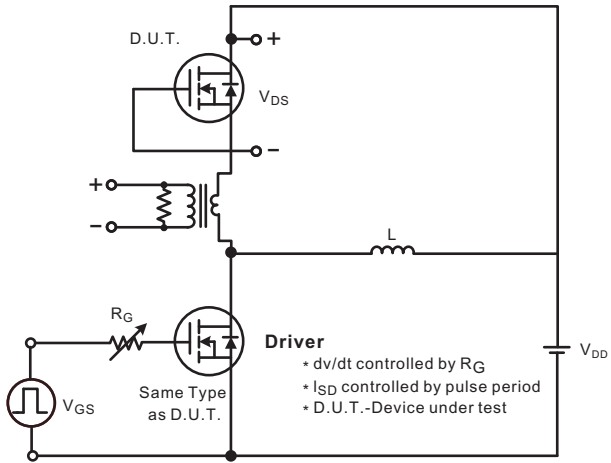


**Fig.13 Transient thermal response curve (for 7N60AF)**

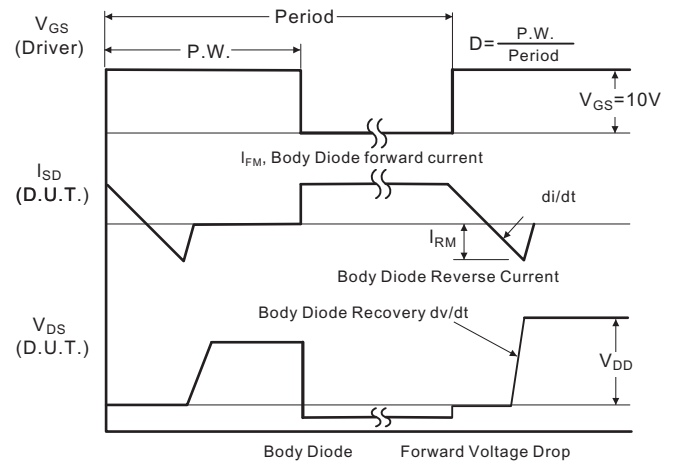


### ■ TEST CIRCUITS AND WAVEFORMS

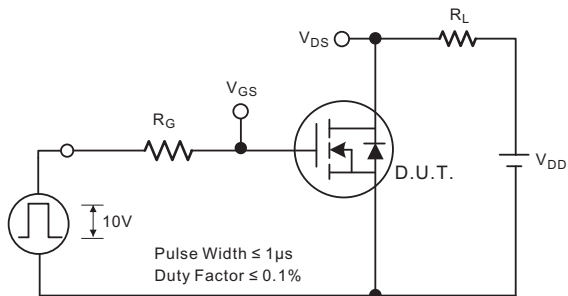
**Fig.1A Peak diode recovery dv/dt test circuit**



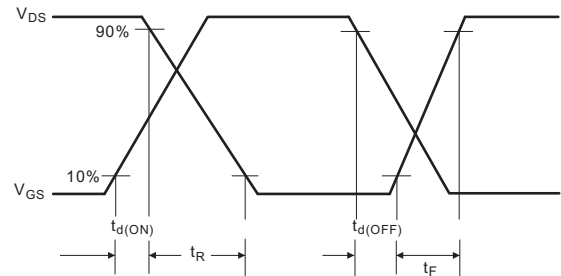
**Fig.1B Peak diode recovery dv/dt waveforms**



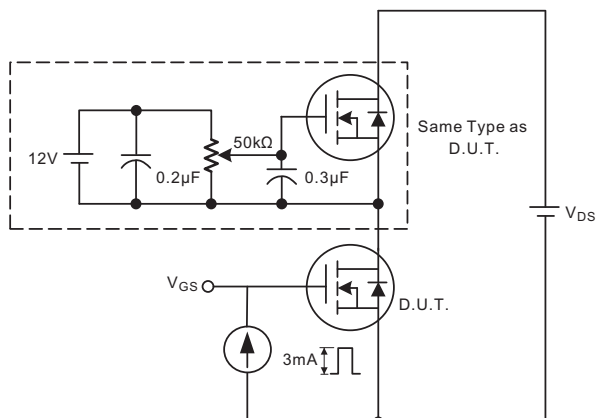
**Fig.2A Switching test circuit**



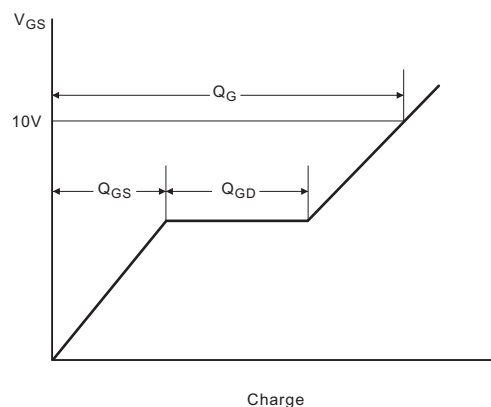
**Fig.2B Switching Waveforms**



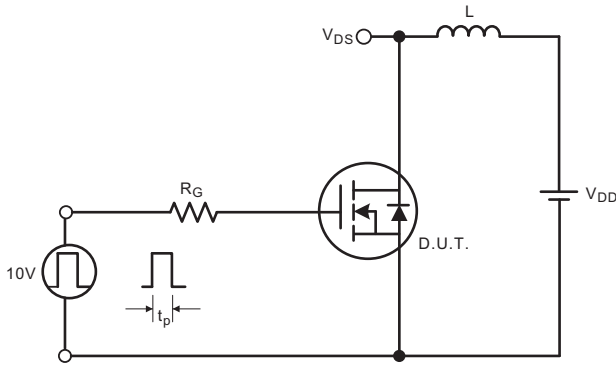
**Fig.3A Gate charge test circuit**



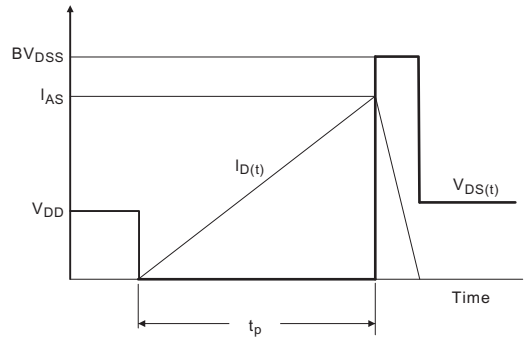
**Fig.3B Gate charge waveform**



**Fig.4A Unclamped Inductive switching test circuit**

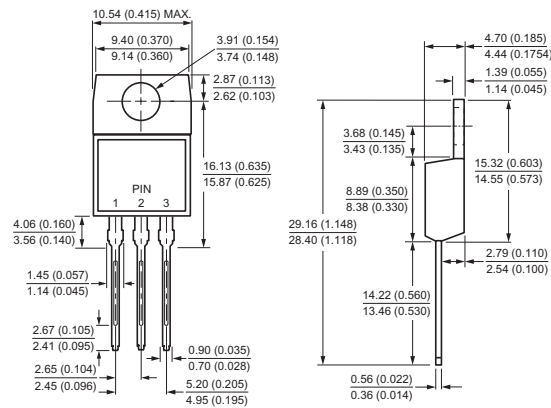


**Fig.4B Unclamped Inductive switching waveforms**

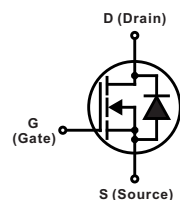
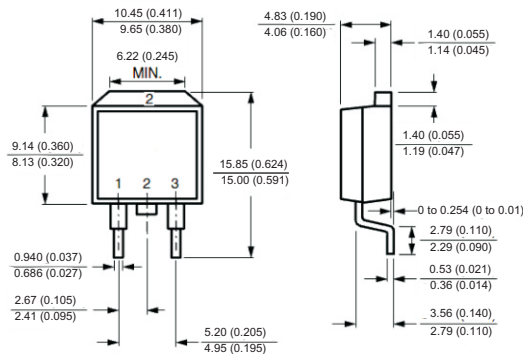


### Case Style

#### TO-220AB



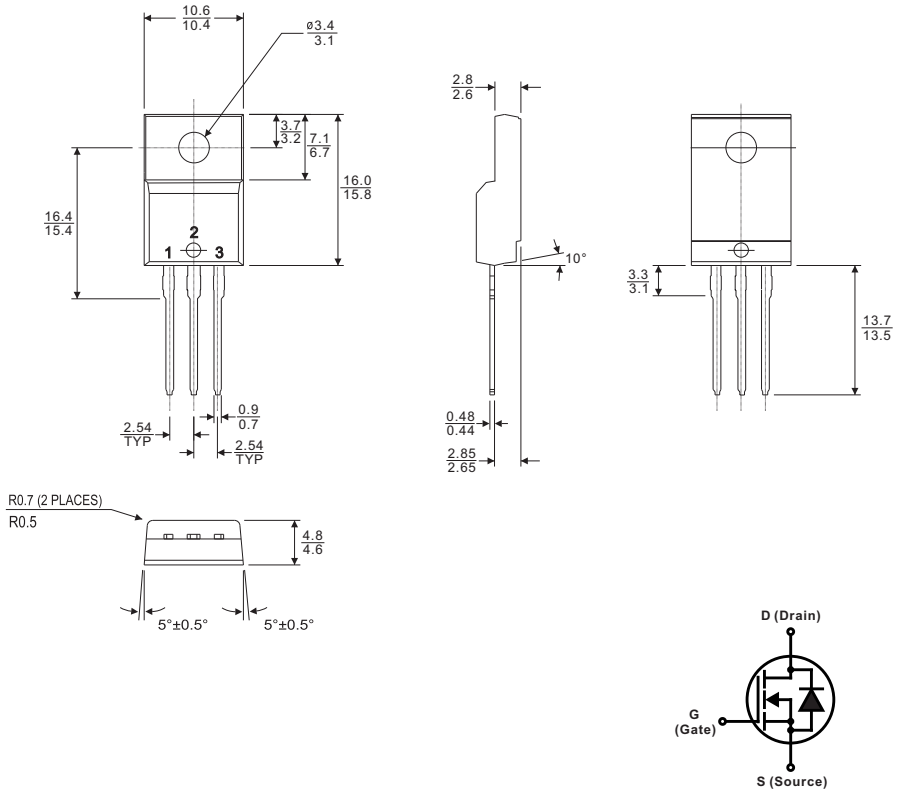
#### TO-263(D<sup>2</sup>PAK)



All dimensions in millimeters(inches)

**Case Style**

**TO-220F**



All dimensions in millimeters